

## Interferometry XII: Applications (AM202)

Part of SPIE's International Symposium on Optical Science and Technology, SPIE's 49th Annual Meeting  
2-6 August 2004 • Colorado Convention Center • Denver, CO, USA

Conference Chairs: **Wolfgang Osten**, Univ. Stuttgart (Germany); **Erik Novak**, Veeco Instruments Inc.

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Interferometry and related optical techniques allow for non-contact inspection of a wide range of objects from macro- to nano-scale. The continuous development of new methods and algorithms both in the laboratory and for industrial applications has greatly refined the science of optical measurements. Today, research environments, industry, and standardization institutes rely on the precision, reliability and flexibility of these techniques, and new applications are rapidly being developed.

Two exciting technical conferences are offered in this Interferometry series: Techniques and Analysis, and Applications. The conferences will cover the latest advances in all areas of interferometry and fringe processing. Recent progress and next-generation developments will be highlighted. The organization of the two interferometry conferences will be coordinated to avoid parallel sessions/short courses/posters and to allow time for visiting the exhibition. Please submit your oral or poster paper(s) to the conference(s) of your choice.

Papers are solicited on the following and related topics:

- aerospace, automotive, and industrial applications
- biological and pharmaceutical applications
- micro- and nano-technology, microelectronics, mechatronics
- optical sensors and measurement systems
- experimental stress analysis
- nondestructive testing and fault recognition
- distance and shape measurement, reverse engineering
- microstructure measurement and surface inspection
- high resolution microscopy and nanoscale metrology
- displacement/strain measurement
- material and structure analysis
- motion/vibration measurement
- optical workshop interferometry
- nonstandard surfaces, quality control
- correlation between experiment and theory
- standardization and traceability.

**Abstract Due Date: 5 January 2004**

**Manuscript Due Date: 10 May 2004**

*Proceedings for this conference will be available at the meeting.*

# Submission of Abstracts for *Optical Science and Technology Symposium, SPIE's 49th Annual Meeting*

Abstract Due Date: 5 January 2004

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## **IMPORTANT!**

Submissions imply the intent of at least one author to register, attend the symposium, present the paper (either orally or in poster format), and submit a full-length manuscript for publication in the conference Proceedings.

All authors (including invited or solicited speakers), program committee members, and session chairs are responsible for registering and paying the reduced author, session chair, program committee registration fee. (Current SPIE Members receive a discount on the registration fee.)

## **Instructions for Submitting Abstracts via Web**

You are **STRONGLY ENCOURAGED** to submit abstracts using the "submit an abstract" link at:

[www.spie.org/info/am](http://www.spie.org/info/am)

Submitting directly on the Web ensures that your abstract will be immediately accessible by the conference chair for review through MySPIE, SPIE's author/chair web site.

Please note! When submitting your abstract you must provide contact information for all authors, summarize your paper, and identify the **contact author** who will receive correspondence about the submission and who must submit the manuscript and all revisions. Please have this information available before you begin the submission process.

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If you do not have web access, you may E-MAIL each abstract separately to: [abstracts@spie.org](mailto:abstracts@spie.org) in [ASCII text \(not encoded\)](#) format. There will be a time delay for abstracts submitted via e-mail as they will not be immediately processed for chair review.

IMPORTANT! To ensure proper processing of your abstract, the SUBJECT line must include only:

**SUBJECT: AM202, Osten/Novak**

Your abstract submission must include all of the following:

1. **PAPER TITLE**
2. **AUTHORS** (principal author first) For each author: First (given) name (initials not acceptable), Last (family) name, Affiliation, Mailing address, Telephone, Fax, and Email address.
3. **PRESENTATION PREFERENCE** "Oral Presentation" or "Poster Presentation."
4. **PRINCIPAL AUTHOR'S BIOGRAPHY** Approximately 50 words.
5. **ABSTRACT TEXT** Approximately 250 words.
6. **KEYWORDS** Maximum of five keywords.

## **Accepted Abstracts**

A CD-ROM of accepted abstracts will be distributed to attendees onsite.

## **Conditions of Acceptance**

- Authors are expected to secure funding for registration fees, travel, and accommodations, independent of SPIE, through their sponsoring organizations before submitting abstracts.
- Only original material should be submitted.
- Commercial papers, papers with no new research/development content, and papers where supporting data or a technical description cannot be given for proprietary reasons will not be accepted for presentation in this symposium.
- Abstracts should contain enough detail to clearly convey the approach and the results of the research.
- Government and company clearance to present and publish should be final at the time of submittal. If you are a DoD contractor, allow at least 60 days for clearance. Authors are required to warrant to SPIE in advance of publication of the Proceedings that all necessary permissions and clearances have been obtained, and that submitting authors are authorized to transfer copyright of the paper to SPIE.

## **Review, Notification, Program Placement**

- To ensure a high-quality conference, all abstracts and Proceedings manuscripts will be reviewed by the Conference Chair/Editor for technical merit and suitability of content. Conference Chair/Editors may require manuscript revision before approving publication, and reserve the right to reject for presentation or publication any paper that does not meet content or presentation expectations. SPIE's decision on whether to accept a presentation or publish a manuscript is final.
- Applicants will be notified of abstract acceptance by mail no later than 10 May 2004. Early notification of acceptance will be placed on SPIE Web the week of 12 April 2004 at [www.spie.org/info/am](http://www.spie.org/info/am)
- Final placement in an oral or poster session is subject to the Chairs' discretion. Instructions for oral and poster presentations will be included in your author kit. All oral and poster presentations are included in the *Proceedings of SPIE*, and require presentation at the meeting and submission of a manuscript.

## **Proceedings of SPIE**

- These conferences will result in full-manuscript Chairs/Editor-reviewed volumes published in the *Proceedings of SPIE*.
- Correctly formatted, ready-to-print manuscripts submitted in English are required for all accepted oral and poster presentations. Electronic submissions are recommended, and result in higher quality reproduction. Submission must be provided in PostScript created with a printer driver compatible with SPIE's online Electronic Manuscript Submission system. Instructions are included in the author kit and from the "Author Info" link at the conference website.
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- Papers published are indexed in leading scientific databases including INSPEC, Ei Compendex, Chemical Abstracts, International Aerospace Abstracts, Index to Scientific and Technical Proceedings and NASA Astrophysical Data System.
- **Late manuscripts may not be published in the conference Proceedings**, whether the conference volume will be published before or after the meeting. The objective of this policy is to better serve the conference participants as well as the technical community at large, by enabling timely publication of the Proceedings.
- **Papers not presented at the meeting will not be published in the conference Proceedings**, except in the case of exceptional circumstances at the discretion of SPIE and the Conference Chairs/Editors.